REMARKS

The Official Action dated June 15, 2005, and Decision on Appeal dated September 25, 2006, have been carefully reviewed and the foregoing amendment is presented in response thereto. Claims 1 through 12 stand rejected under 35 U.S.C. §102(e) as being anticipated by U.S. Patent No. 6,381,556 issued to Kazemi et al.

The foregoing amendment presents changes to claims 1, 2, 7 and 8 in order to more clearly recite the invention, and distinguish the recited invention from the cited prior art.

Claim Rejections – 35 U.S.C. §102

It is believed that the amendment to claims 1, 2 7, and 8 presented above overcomes the rejection of the claims 1 through 12 under 35 U.S.C. §102(e) as being anticipated by Kazemi et al.

The present application describes and claims a system and method that stores product manufacturing parameters within a database, analyzes the stored product manufacturing parameters to define one or more normal parameter subsets, compares manufacturing parameters associated with at least one product with the manufacturing parameters contained within the first normal subset and detects manufacturing parameters associated with the at least on product that are not contained within the normal subset in order to identify manufacturing anomalies. The present application includes two independent claims: claims 1 and 7. The remaining claims in the present application depend from claim 1 or claim 7. Independent method claim 1, as amended, recites:

1. A method for identifying manufacturing anomalies in a manufacturing system comprising a plurality of products which are manufactured with a plurality of manufacturing parameters, the method comprising the steps of

storing the plurality of manufacturing parameters in a data warehouse;

applying a data mining program to perform the steps of:

analyzing the stored manufacturing parameters to define a first normal subset, said first normal subset comprising a subset of said plurality of manufacturing parameters of products which show similar performance ratings;

comparing manufacturing parameters associated with at least one product with the manufacturing parameters contained within said first normal subset;

detecting at least one manufacturing parameter associated with said at least one product that is excluded from the first normal subset; and

reporting the at least one detected manufacturing parameter.

Independent apparatus claim 7, as amended, recites:

7. A system for identifying manufacturing anomalies in a manufacturing system comprising a plurality of products which are manufactured with a plurality of manufacturing parameters, comprising:

7. (currently amended) A system for identifying manufacturing anomalies in a manufacturing system comprising a plurality of products which are manufactured with a plurality of manufacturing parameters, comprising:

a data warehouse for storing the plurality of manufacturing parameters;

a data mining program applied to the data warehouse for analyzing the stored manufacturing parameters to define a first normal subset, said first normal subset comprising a subset of said plurality of manufacturing parameters of products which show similar performance ratings, comparing manufacturing parameters associated with at least one product with the manufacturing parameters contained within said first normal subset, and detecting at least one manufacturing parameter associated with said at least one product that is excluded from the first normal subset; and

a reporting means for reporting the at least one detected manufacturing parameter.

It is believed that the invention as recited in each one of the claims of the present application differs from the system taught in Kazemi et al. It is not seen that Kamezi et al. teaches or suggests the steps of

analyzing the stored manufacturing parameters to define a first normal subset, said first normal subset comprising a subset of said plurality of manufacturing parameters of products which show similar performance ratings;

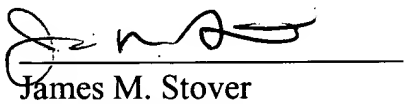
comparing manufacturing parameters associated with at least one product with the manufacturing parameters contained within said first normal subset; and

detecting at least one manufacturing parameter associated with said at least one product that is excluded from the first normal subset.

The steps set forth immediately above are included in each one of method claims 1 through 6 of the present application. Similar limitations are contained in each one of apparatus claims 7 through 12. As these limitations are not taught or suggested in Kazemi et al., it is believed that claims 1 through 12, as amended are patentable over Kazemi et al.

In view of the foregoing amendments and remarks, it is believed that the application, including claims 1 through 14, as amended, is in condition for allowance. Early and favorable action is respectfully requested.

Respectfully submitted,



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